



US00D838609S

(12) **United States Design Patent** (10) **Patent No.:** **US D838,609 S**
Kim (45) **Date of Patent:** **** Jan. 22, 2019**

(54) **APPARATUS FOR DETECTING PARTICLE ON TEST FILM**

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(**) Term: **15 Years**

(21) Appl. No.: **29/617,261**

(22) Filed: **Sep. 13, 2017**

(30) **Foreign Application Priority Data**

Aug. 2, 2017 (KR) 30-2017-0035752

(51) **LOC (11) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/46; D10/75; D10/81; D24/216**

(58) **Field of Classification Search**
USPC D10/46, 75, 81; D24/216, 232, 233, 234;
356/237.1, 237.2, 237.3, 237.4, 237.5,
356/237.6, 239.7, 239.8

CPC G01N 1/04; G01N 1/20; G01N 15/02;
G01N 15/0205; G01N 21/8803; G01N
2001/028

See application file for complete search history.

(56) **References Cited**

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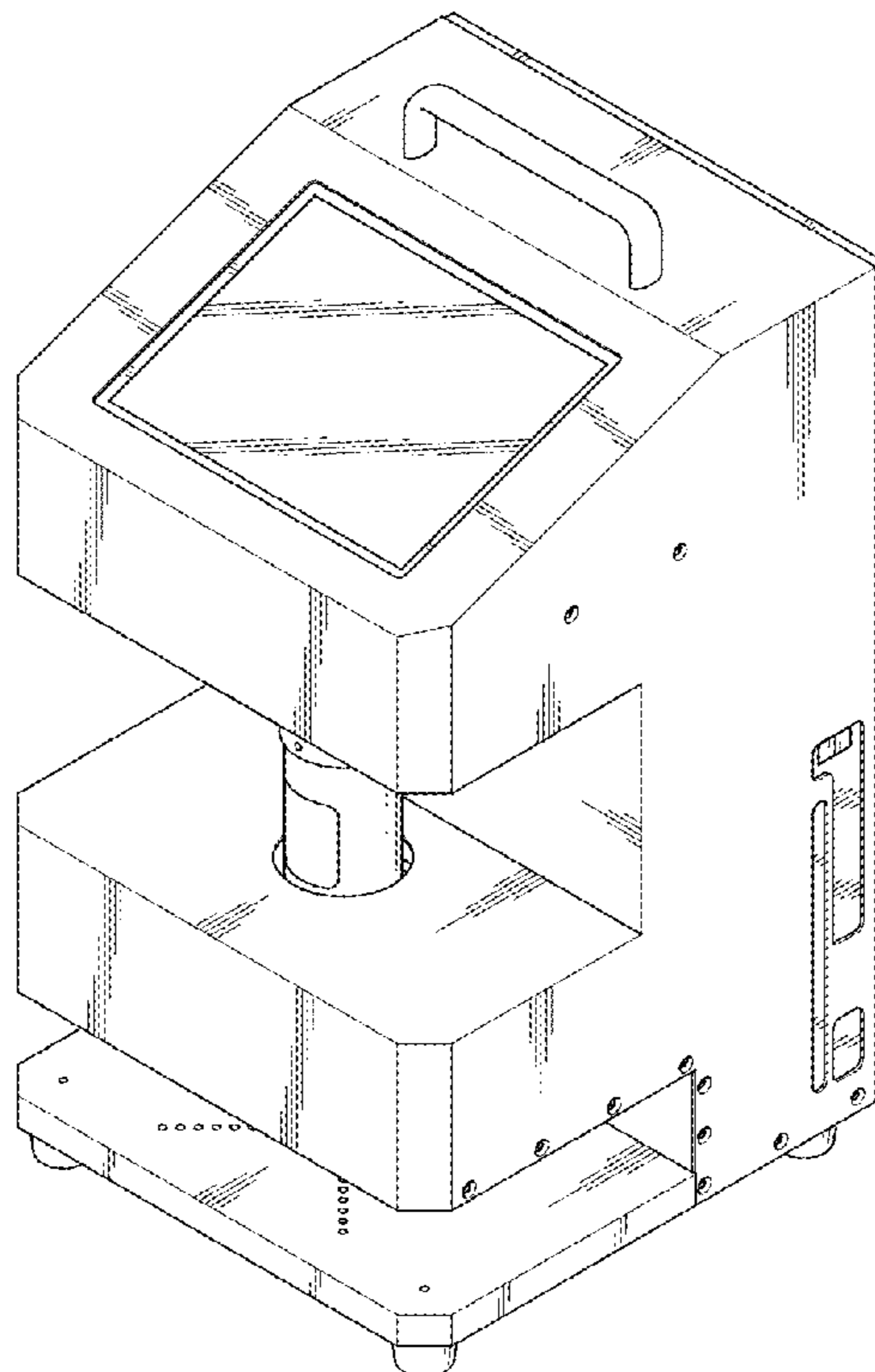
(57) **CLAIM**

I claim, the ornamental design for an apparatus for detecting particles on test film, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of an apparatus for detecting particles on test film, showing my new design; FIG. 2 is a front elevational view thereof; FIG. 3 is a rear elevational view thereof; FIG. 4 is a left side elevational view thereof; FIG. 5 is a right side elevational view thereof; FIG. 6 is a top plan view thereof; and, FIG. 7 is a bottom plan view thereof.

1 Claim, 7 Drawing Sheets



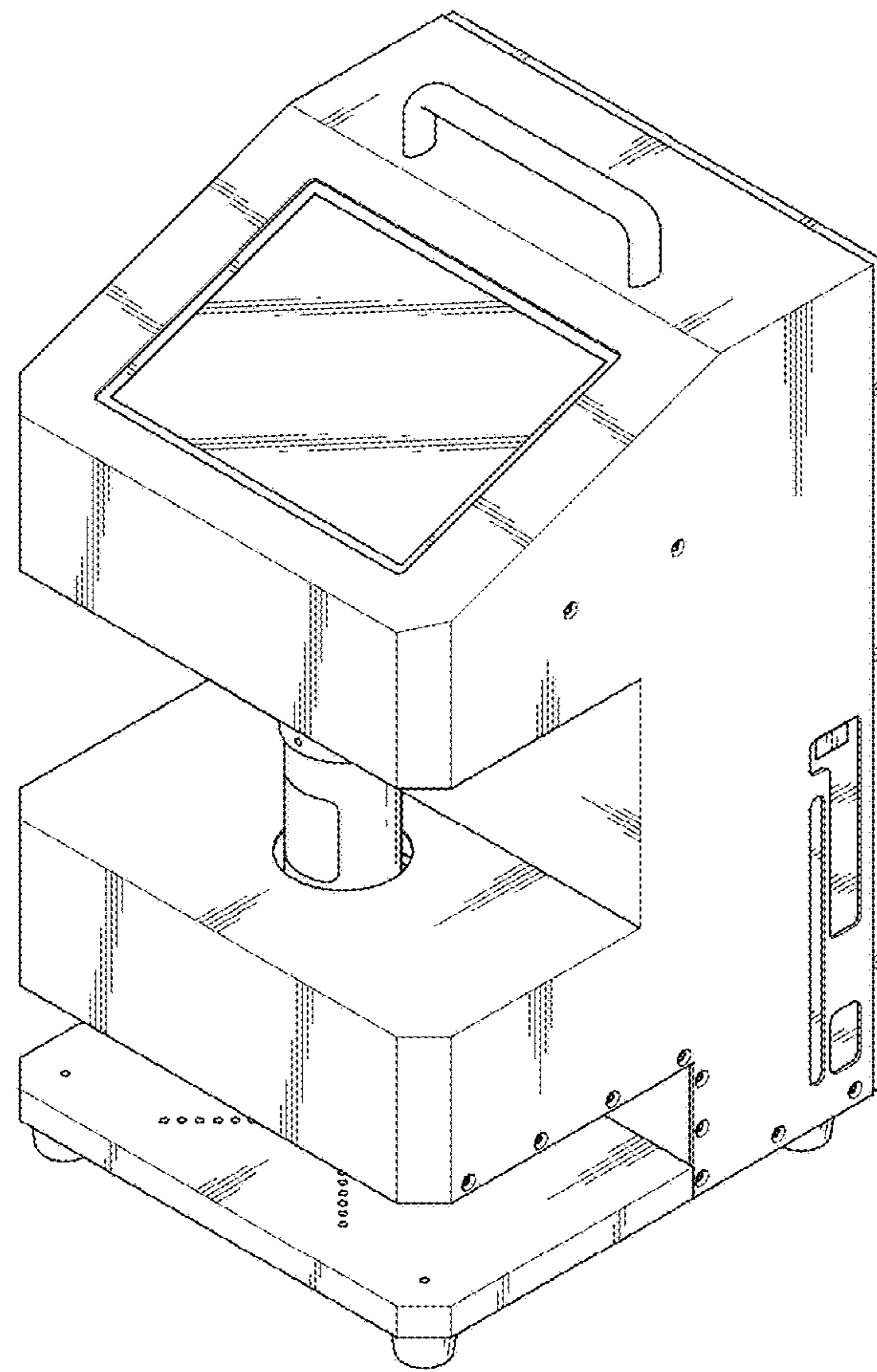


FIG. 1

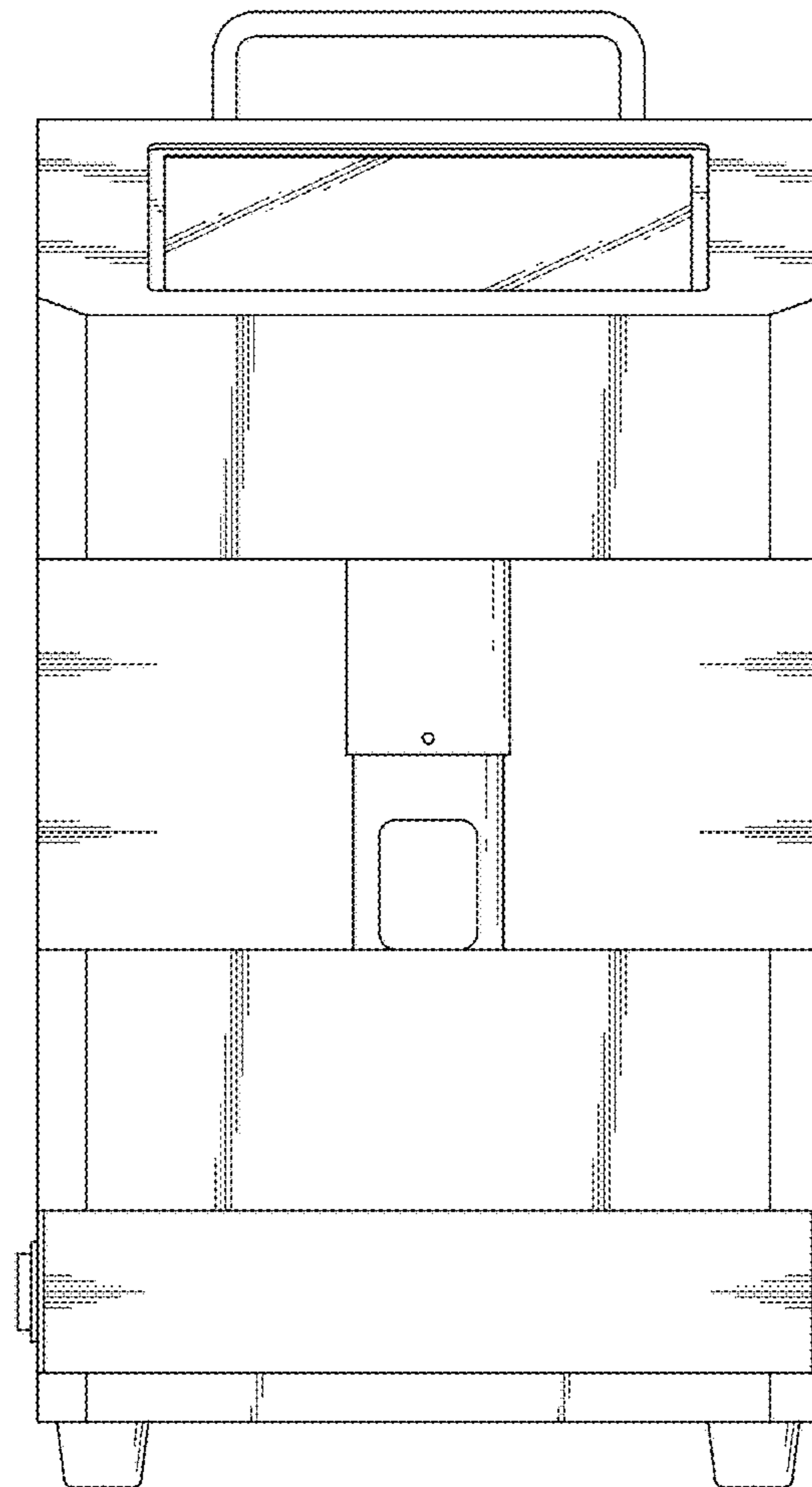


FIG. 2

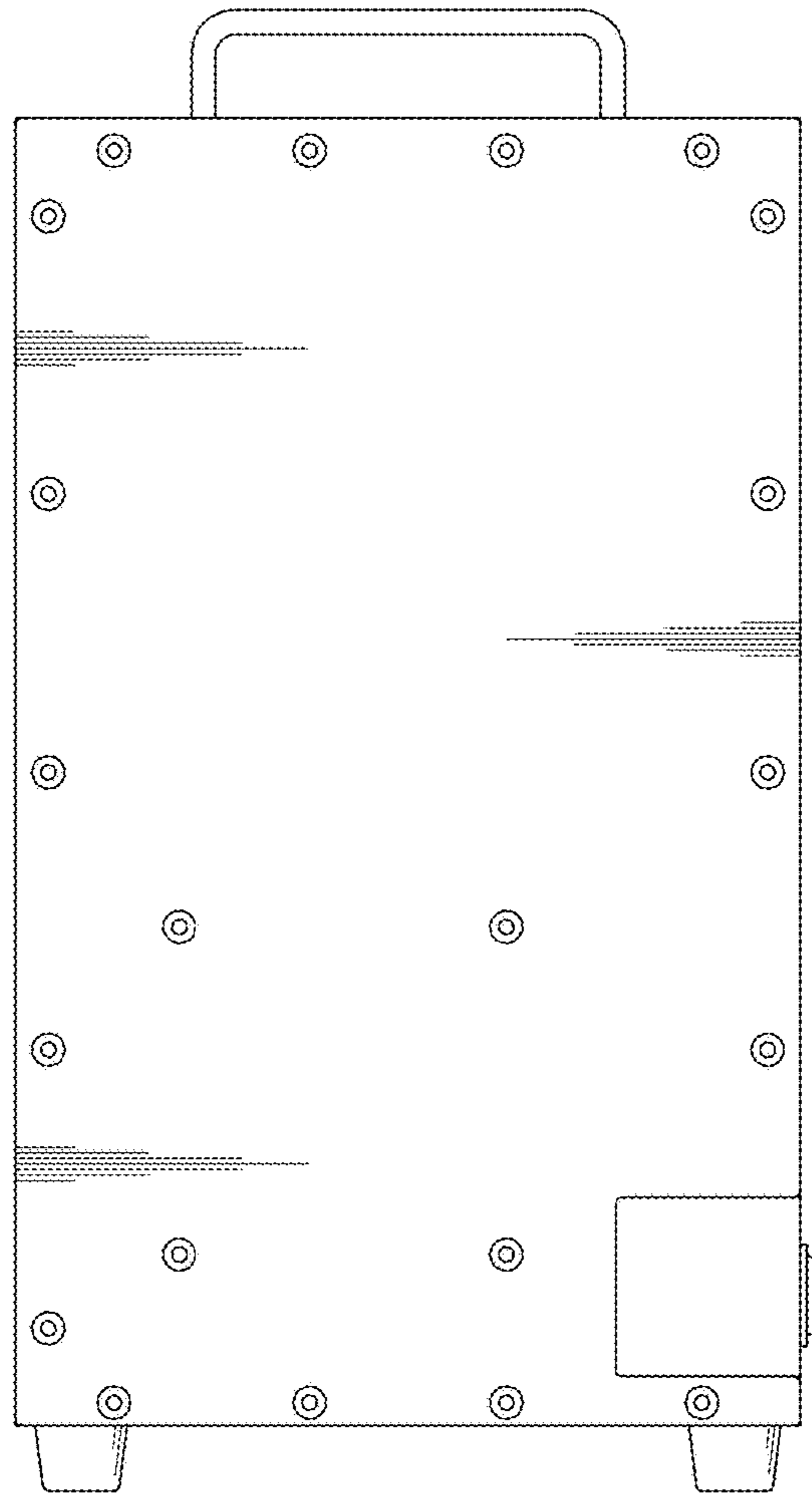


FIG. 3

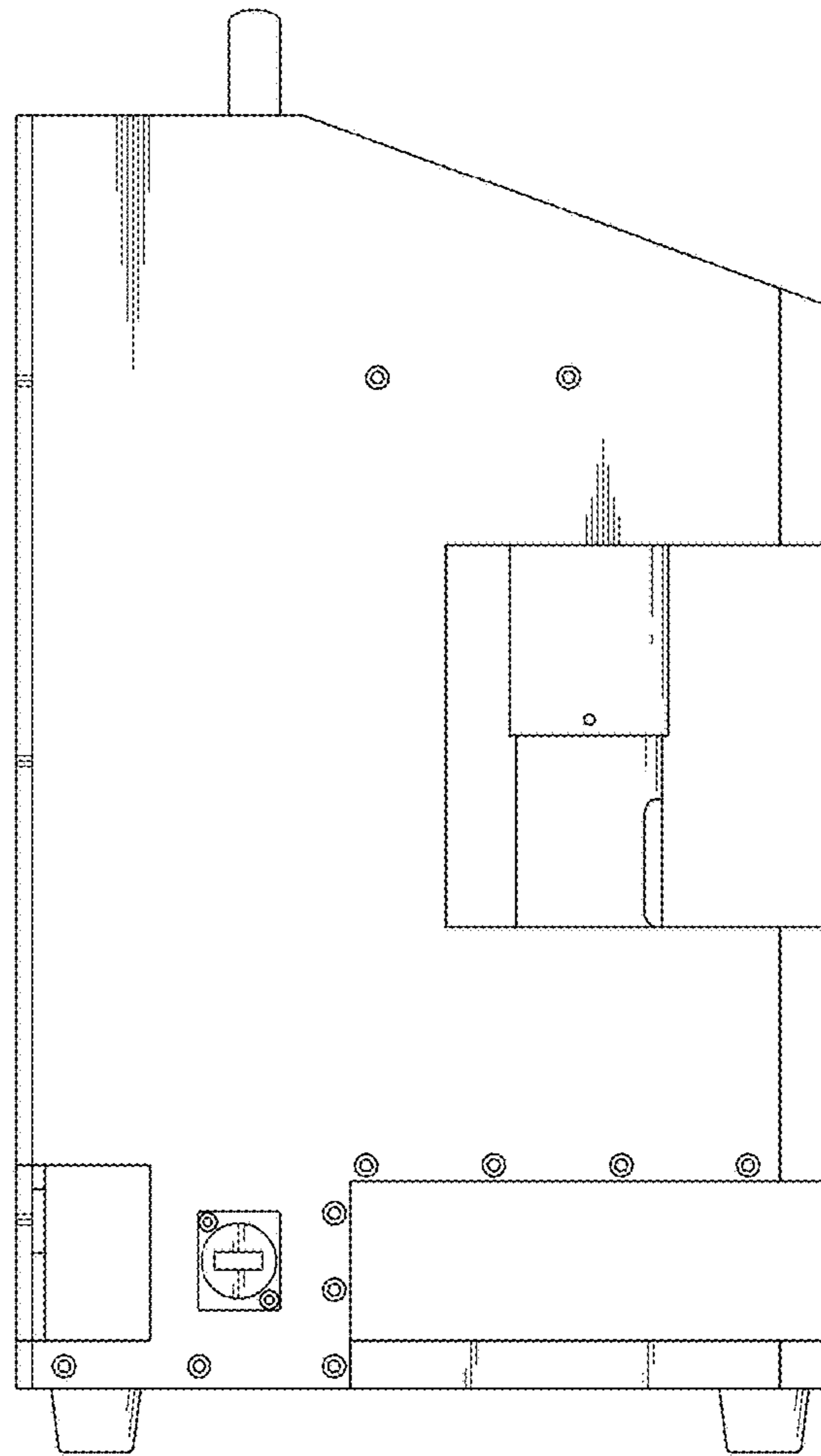


FIG. 4

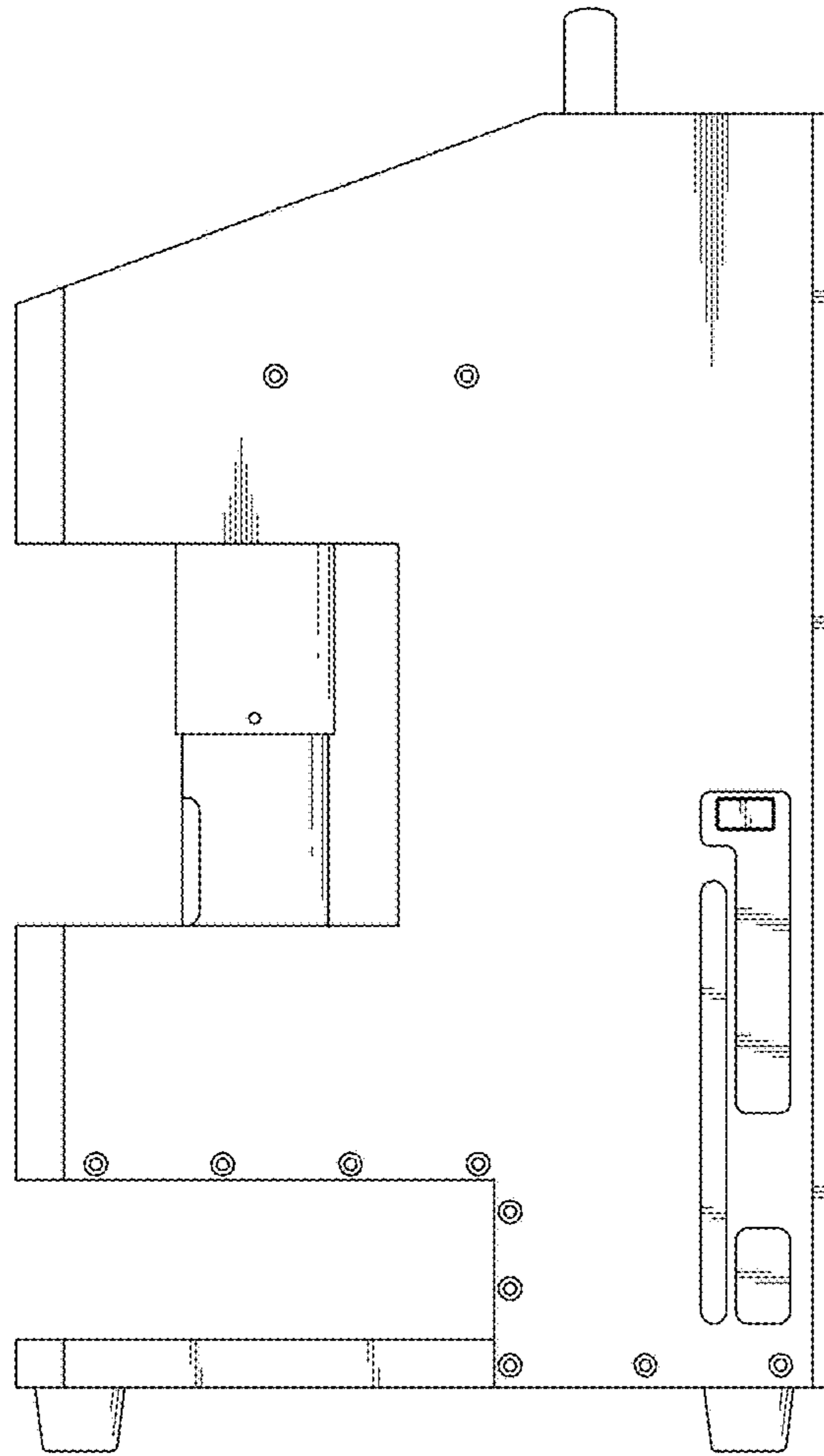


FIG. 5

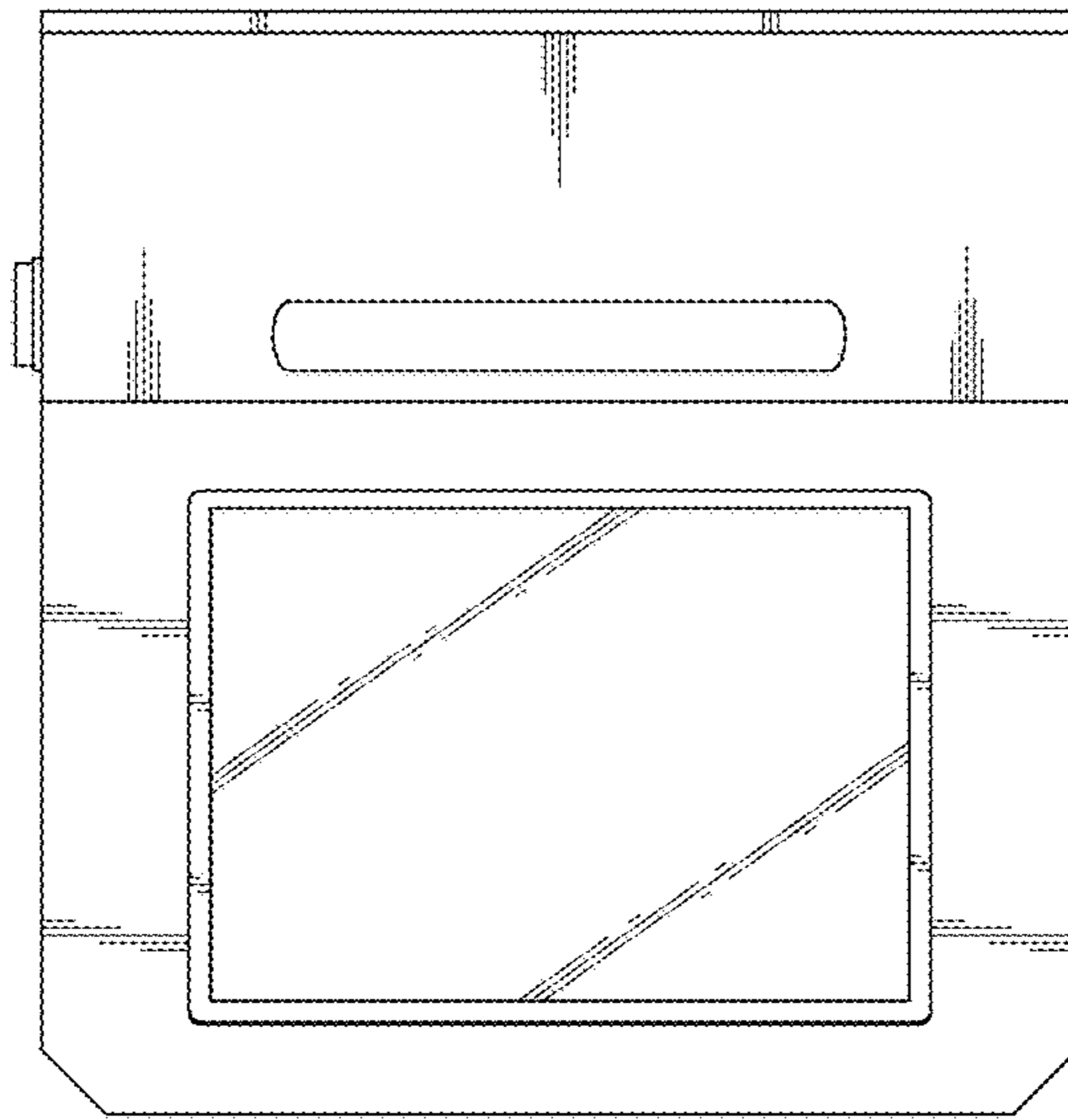


FIG. 6

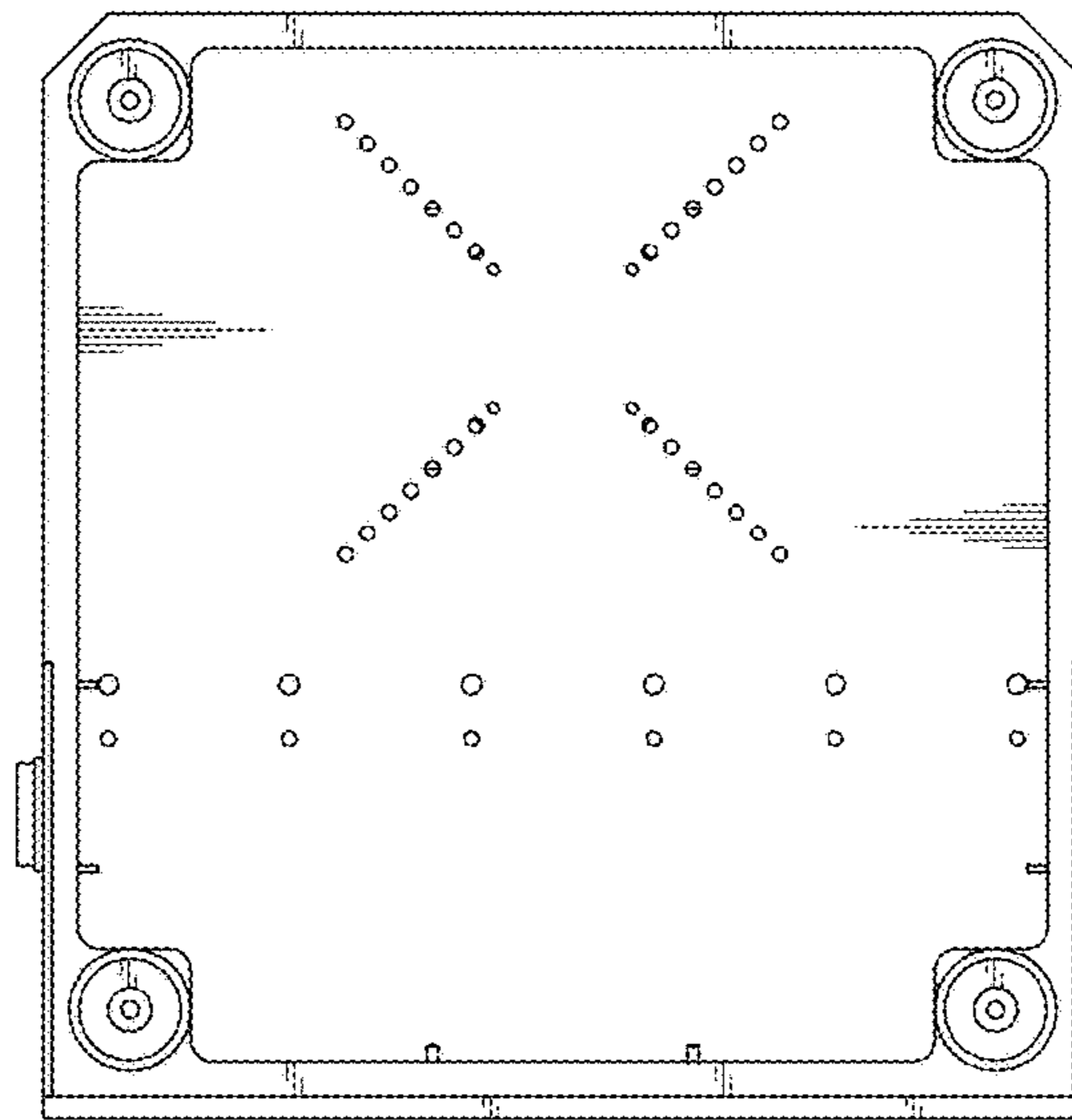


FIG. 7